

P700

RF Voltage Probe



Short description

The P700 RF voltage probe is used to measure the disturbance emission of single IC pins. The voltage probe consists of a P700 basic body and changeable probe tips (TS 701 - TS 705, with an integrated preamplifier), which differ in their internal resistances. The probe tip can be precisely and quickly contacted to IC pins. Measurements with the P700 probe and its corresponding probe tips guarantee a high precision when repeated and a high level of comparability of individual electromagnetic emission measurements.

The RF voltage probe has high-resistance inputs with capacitive coupling. Due to the very low parasitic capacity RF voltages can be measured at the device under test's output pins and input pins without a noticeable current stressing the pins. For measuring tasks requiring a high-resistance voltage probe the TS 701 probe tip with 1.5 kOhm is available. For measuring tasks requiring a low-resistance probe voltage or adapted measurements the TS 705 (50 Ohm) and TS 706 (100 Ohm) probe tips are available. The P700 voltage probe combined with its TS 751 probe tip (coupling network 150 Ohm) allow for the measurement of conducted electromagnetic emission according to IEC 61967-4 of integrated circuits.

Technical parameters

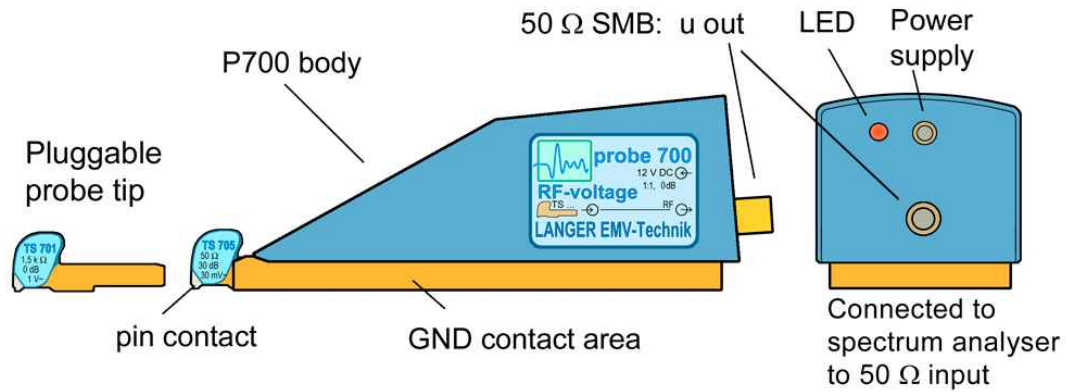
Measuring output	50 Ω , SMB
Supply voltage	12 / DC

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LANGER
EMV-Technik

Design, view 1



Application with P700

